

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/177,572	TERASHIMA ET AL.	
Examiner	Art Unit	
Kevin M. Nguyen	2674	

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Class	Subclass	Date	Examiner
Update	search	11/30/2005	KMN
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INT	ERFERENC	CE SEARCH	ED
Class	Subclass	Date	Examiner
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Interferer search, so history p	ee search	11/30/2005	KMN

SEARCH NOT (INCLUDING SEARCH		<b>)</b>
	DATE	EXMR
Fext search and Inventor search, see search history printout.	11/30/2005	KMN
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